

---

---

***New Radiation Issues for Spacecraft  
Microelectronics -Commercial Off-The Shelf  
(COTS)***

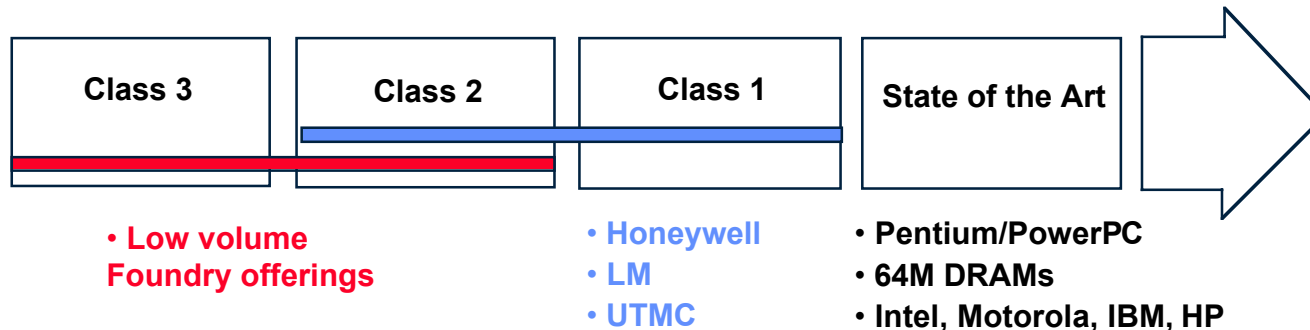
**Chuck Barnes  
Radiation Testing and Failure Analysis Group  
Electronic Parts Engineering Office (507)  
charles.e.barnes@jpl.nasa.gov  
(818) 354-4467**

**January 29, 1998**



## Commercial-off-the-shelf (COTS) parts in space

- Access to high performance, state-of-the-art microelectronics - difficult to achieve with small, custom parts purchases

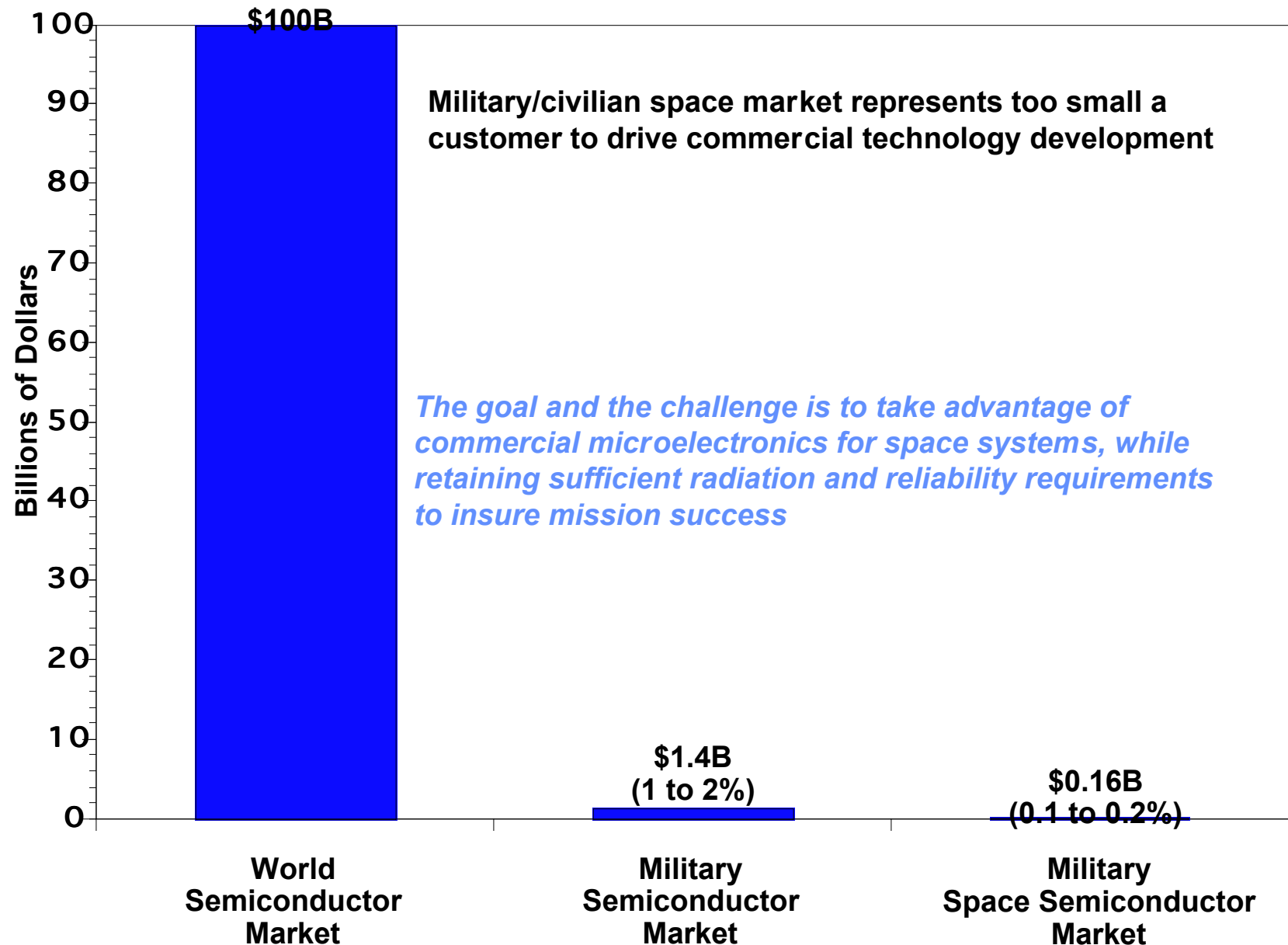


- Large, standardized software base
- Lower cost
  - ◆ Although upscreening can raise cost substantially
  - ◆ Parts are small fraction of total satellite/spacecraft cost (5 to 10%), but this cost will be relatively higher in future
- Decreased availability of parts off rad-hard processing lines
- Greater government reliance on industry standards and specifications for part procurement (Perry Directive)
- For NASA, new paradigm of “Better, Faster, Cheaper” allows for risk management rather than complete elimination of risk, and requires quick, inexpensive procurements



# World Semiconductor Device/Circuit Business

JPL  
Electronic  
Parts  
Engineering



- Small customers (space) cannot drive development, specifications or requirements
- Life cycle costs can actually be higher for COTS-intensive satellite due to added testing, part and system failure, system re-work, added cost of shielding
- Reliability data on COTS is often unknown or unavailable to small customer
- Commercial competitiveness to reduce cost, improve performance can jeopardize availability of specific parts required in future systems
- Space applications do not usually allow for repair or replacement
- Plastic encapsulated microcircuits (PEMs) are very popular and more reliable than previously, but can still pose problems for space use
  - ◆ Handling and assembly problems
  - ◆ Encapsulants vary in composition and properties
  - ◆ Moisture absorption - “popcorning”
  - ◆ Limited temperature ranges
  - ◆ Differences in thermal expansion coefficients are a problem with thermal cycling
- ***Radiation is a big problem***

- **Reliability and RHA often unknown**
- **Radiation is unique**
  - ◆ Can't leverage off other high rel users like automotive
- **TID response depends on process**
  - ◆ "Positive" changes can reduce radiation tolerance
  - ◆ NASA technical penetration often difficult
- **SEE depends on circuit design and dimensions**
  - ◆ Commercial vendor can change these without notice
- **No good way of predicting radiation response without testing**
  - ◆ *IRONY* – Process knowledge, testability and penetration are where you don't need them – rad hard process lines
- **Packaging can make RHA hard to establish**
  - ◆ Flip chip bonding
  - ◆ SEE hard to do on plastics
  - ◆ Multichip modules (MCMs) hard to test

- **Work with commercial suppliers to obtain reliability and radiation data**
- **Encourage data and information sharing among commercial parts vendors, users and the government**
- **Evaluate commercial process lines, when possible, to determine SPC, workmanship quality, reliability and radiation hardness**
  - ◆ Similar to QML audits performed by DESC
  - ◆ Must include assessment of quality of data
- **Re-examine screening and failure analysis requirements and techniques to determine if they are really needed and their relevance to COTS usage**
- **Develop process line “tweaks” that will enhance reliability and/or radiation tolerance but are minor enough to be implemented by commercial parts vendors**
- **Evaluate design techniques for introducing radiation hardness and reliability through design changes**
  - ◆ Single event effects are amenable to this, but not total dose effects
  - ◆ Particularly important for SEL - that’s all many users care about
- **Maintain a vigorous, healthy test activity to provide continuous evaluation of radiation tolerance and reliability**
  - ◆ As noted earlier, rad tolerance can change without notice
- **Through working groups and consortia, evaluate standards and specifications and establish new standards for procurement**



- **Radiation analysis and testing of COTS parts**
  - ◆ Support to NASA flight projects
  - ◆ Cheaper, easier test methodologies
- **Radiation risk mitigation techniques**
  - ◆ Latchup mitigation
    - Circuit solutions
    - Neutron irradiation
  - ◆ RadPak, shielding
  - ◆ Mitigation of hard errors, dielectric rupture
  - ◆ Software mitigation techniques
- **Evaluation, research**
  - ◆ Advanced COTS technologies
    - FPGAs, DRAMs, highly scaled devices, MCMs, MEMS, photonics, III-V-based technologies
  - ◆ New radiation phenomena
    - Enhanced low dose rate effects
    - FPGA anti-fuse rupture and connection
- **Dissemination of radiation data**
  - ◆ RADATA data bank
  - ◆ URL: <http://radnet.jpl.nasa.gov>



- It is inevitable that space flight systems will use COTS to a greater degree in the future; already taking place to a limited extent
- There are still many space applications where it would be very difficult to use large percentages of COTS parts
- Life cycle costs can actually be less for radiation hardened parts than for COTS
- Watch out for hybrids - can contain vulnerable parts
- No single, elegant solution exists for RHA problems associated with use of advanced commercial parts in space
  - ◆ Mission performance and radiation environment requirements can vary drastically
  - ◆ A variety of solutions can be used for any given mission
    - Establish RHA with rad testing
    - Disseminate rad data to designers so they can use it early in project cycle
    - Use various shielding techniques
    - Use software and hardware mitigation methods
    - Use modified commercial designs that are more rad tolerant
    - Go to captive lines for rad hard product
  - ◆ *Implementation of solutions is more difficult than identifying solutions*
    - Projects have no funds for RHA early in cycle